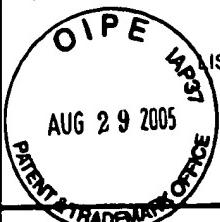


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-356	SERIAL NO. 10/626,876		
 <b>AUG 29 2005</b> <b>LAPST</b>		<b>LIST OF ART CITED BY APPLICANT</b> <small>(Use several sheets if necessary)</small>			<b>APPLICANT:</b> Micron Technology, Inc.			
					FILING DATE July 24, 2003	GROUP 2635		
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<i>EJH</i>	AA	4,697,184	09/1987	CHEAL ET AL.	342	28		
<i>J</i>	AB	5,055,968	10/1991	NISHI ET AL.	361	395		
<i>J</i>	AC	5,345,231	09/1994	KOO ET AL.	340	870.31		
<i>EJH</i>	AD	5,437,041	07/1995	WAKABAYASHI ET AL.	395	800		
	AE							
	AF							
	AG							
	AH							
<b>FOREIGN PATENT DOCUMENTS</b>								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>EJH</i>	AI	0 675 425 A2	10/4/95	EPO (Fujitsu Personal Systems)	G06F	1/32	X	
<i>J</i>	AI	0 675 425 A3	10/4/95	EPO (Fujitsu Personal Systems)	G06F	1/32	X	
<i>J</i>	AK	0 481 485 A2	4/22/92	EPO (NEC Corporation)	G06F	1/04	X	
<i>EJH</i>	AL	0 481 485 A3	4/22/92	EPO (NEC Corporation)	G06F	1/04	X	
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AM							
	AN							
	AO							
EXAMINER <i>EJH</i>		DATE CONSIDERED <i>9-22-05</i>						
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								